Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/692,800	MIYAKE ET AL.
Examiner	Art Unit

Benjamin P. Geib

2181

	SEARCHED				
Class	Subclass	Date	Examiner		
712	244	12/20/2007	BPG		
717	129	12/20/2007	BPG		
		1			

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Updated EAST search	12/20/2007	BPG
NPL search (Google Scholar, IEEE Xplore)	12/20/2007	BPG
Inventor name search	12/20/2007	BPG